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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

RESPONSE UNDER 37 CFR 1.116  
EXPEDITED PROCEDURE  
EXAMINING GROUP 2829

PATENT APPLICATION  
Docket No. 8750-17  
Client No. SPX2001100010US

In re application of: Sang-Eun LEE and JAe-Sung HAN

Serial No. 10/068,152

Examiner: Hollinton, Jermele M.

Confirmation No. 7500

Filed: February 6, 2002

Art Unit: 2829

For: METHOD OF IDENTIFYING AND ANALYZING SEMICONDUCTOR  
CHIP DEFECTS

MAIL STOP AF  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

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Responsive to the Final Office Action dated September 25, 2003, enclosed is an amendment in the above-identified application.

The fee has been calculated as shown below.

CLAIMS AS AMENDED					
For:	Number After Amendment	Previous Number	Extra	Rate	Additional Fee
Total Claims	20	20	0	x \$18 =	\$0
Independent Claims	3	3	0	x \$86 =	\$0
TOTAL ADDITIONAL FEE FOR THIS AMENDMENT					\$0

\*greater of twenty (20) or number for which fee has been paid

\*\*greater of three (3) or number for which fee has been paid

☒ Any deficiency or overpayment should be charged or credited to deposit account number 13-1703.

Customer No. 20575

Respectfully submitted,

MARGER JOHNSON & McCOLLOM, P.C.

Kevin S. Ross  
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**RESPONSE AFTER FINAL REJECTION UNDER 37 CFR 1.116**

Responsive to the Final Office Action, Paper No. 5, dated September 25, 2003, please amend the application as follows.

**Amendments to the Claims** are reflected in the listing of claims which begins on page 2 of this paper.

**Remarks/Arguments** begin on page 5 of this paper.

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